

**Search Notes**

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Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

ANDO, TAKESHI

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
Search	Update	5/25/2006	CH
455	432.1	5/29/2006	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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